MOSFET - Power, N-Channel, SUPERFET® III, FAST

650 V, 360 mΩ, 10 A

NTPF360N65S3H

Description

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provides superior switching performance, and withstand extreme dv/dt rate.

Consequently, SUPERFET III FAST MOSFET series helps minimize various power systems and improve system efficiency.

Features

- $700 \text{ V} @ \text{T}_{\text{J}} = 150^{\circ}\text{C}$
- Typ. $R_{DS(on)} = 296 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q_g = 17.5 nC)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 180 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

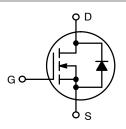
- Computing / Display Power Supplies
- Telecom / Server Power Supplies
- Industrial Power Supplies
- Lighting / Charger / Adapter

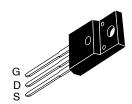


ON Semiconductor®

www.onsemi.com

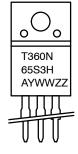
V _{DSS} R _{DS(ON)} MAX		I _D MAX	
650 V	360 mΩ @ 10 V	10 A	





TO-220 FULLPAK CASE 221D

MARKING DIAGRAM



T360N65S3H = Specific Device Code

A = Assembly Location

Y = Year

WW = Work Week
ZZ = Lot Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, Unless otherwise specified)

Symbol	Parameter		Value	Unit
V _{DSS}	Drain to Source Voltage		650	V
V_{GSS}	Gate to Source Voltage	DC	±30	V
		AC (f > 1 Hz)	±30	V
I _D	Drain Current	Continuous (T _C = 25°C)	10*	Α
		Continuous (T _C = 100°C)	6*	
I _{DM}	Drain Current	Pulsed (Note 1)	28*	Α
E _{AS}	Single Pulsed Avalanche Energy (Note 2)	ingle Pulsed Avalanche Energy (Note 2)		mJ
I _{AS}	Avalanche Current (Note 2)			Α
E _{AR}	Repetitive Avalanche Energy (Note 1)			mJ
dv/dt	dv/dt MOSFET dv/dt		120	V/ns
	Peak Diode Recovery dv/dt (Note 3)		20	
P_{D}	Power Dissipation	(T _C = 25°C)	26	W
		Derate Above 25°C	0.21	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		−55 to +150	°C
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 s		260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.
*Drain current limited by maximum junction temperature.

THERMAL CHARACTERISTICS

Symbol	Symbol Parameter		Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case, Max.	4.71	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient, Max.	esistance, Junction to Ambient, Max. 62.5	

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Shipping
NTPF360N65S3H	T360N65S3H	TO-220 FULLPAK	50 Units / Tube

^{1.} Repetitive rating: pulse-width limited by maximum junction temperature. 2. $I_{AS} = 1.9 \text{ A}$, $R_G = 25 \Omega$, starting $T_J = 25^{\circ}\text{C}$. 3. $I_{SD} \le 5.0 \text{ A}$, di/dt $\le 200 \text{ A}/\mu\text{s}$, $V_{DD} \le 400 \text{ V}$, starting $T_J = 25^{\circ}\text{C}$.

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
OFF CHARACT	ERISTICS			•	•	
BV _{DSS}	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V, } I_D = 1 \text{ mA, } T_J = 25^{\circ}\text{C}$	650			V
		V _{GS} = 0 V, I _D = 1 mA, T _J = 150°C	700			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I _D = 10 mA, Referenced to 25°C		0.63		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 650 V, V _{GS} = 0 V			1	μΑ
		$V_{DS} = 520 \text{ V}, T_{C} = 125^{\circ}\text{C}$		2.6		
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
ON CHARACTE	ERISTICS		•			
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 0.7 \text{ mA}$	2.4		4.0	V
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 5.0 A		296	360	mΩ
9FS	Forward Transconductance	$V_{DS} = 20 \text{ V}, I_D = 5.0 \text{ A}$		11.2		S
YNAMIC CHA	RACTERISTICS				•	•
C _{iss}	Input Capacitance	V _{DS} = 400 V, V _{GS} = 0 V, f = 250 kHz		916		pF
C _{oss}	Output Capacitance			15		pF
C _{oss(eff.)}	Effective Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V		180		pF
C _{oss(er.)}	Energy Related Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V		24		pF
Q _{g(tot)}	Total Gate Charge at 10 V			17.5		nC
Q _{gs}	Gate to Source Gate Charge	$V_{DS} = 400 \text{ V}, I_{D} = 5.0 \text{ A}, V_{GS} = 10 \text{ V}$ (Note 4)		4.3		nC
Q _{gd}	Gate to Drain "Miller" Charge	(1333-1)		5		nC
ESR	Equivalent Series Resistance	f = 1 MHz		0.9		Ω
WITCHING CH	IARACTERISTICS					
t _{d(on)}	Turn-On Delay Time			15		ns
t _r	Turn-On Rise Time	$V_{DD} = 400 \text{ V}, I_D = 5.0 \text{ A},$		6.7		ns
t _{d(off)}	Turn-Off Delay Time	$V_{DD} = 400 \text{ V}, I_D = 5.0 \text{ A}, \ V_{GS} = 10 \text{ V}, R_g = 12 \Omega \ (\text{Note 4})$		45		ns
t _f	Turn-Off Fall Time			7		ns
OURCE-DRAI	N DIODE CHARACTERISTICS		•			
I _S	Maximum Continuous Source to Drain [Diode Forward Current			10	Α
I _{SM}	Maximum Pulsed Source to Drain Diode	e Forward Current			28	Α
V_{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 5.0 A			1.2	٧
t _{rr}	Reverse Recovery Time	V _{DD} = 400 V, I _{SD} = 5.0 A,		204		ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$		1.9		μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of operating temperature typical characteristics.

TYPICAL CHARACTERISTICS

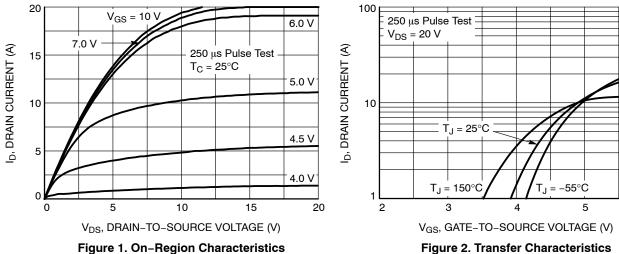


Figure 1. On-Region Characteristics

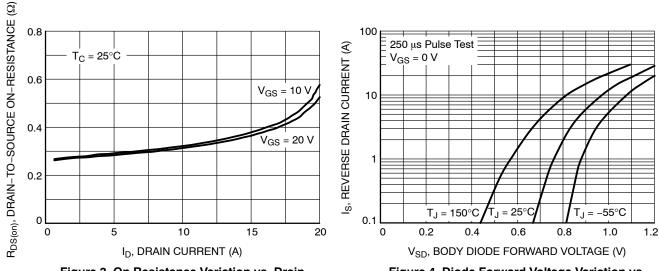


Figure 3. On Resistance Variation vs. Drain **Current and Gate Voltage**

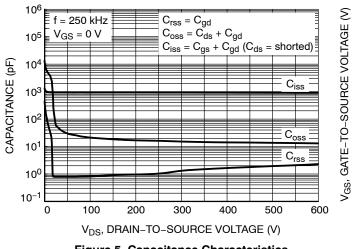


Figure 5. Capacitance Characteristics

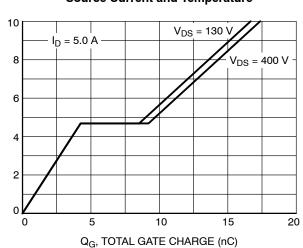


Figure 6. Gate Charge Characteristics

6

TYPICAL CHARACTERISTICS

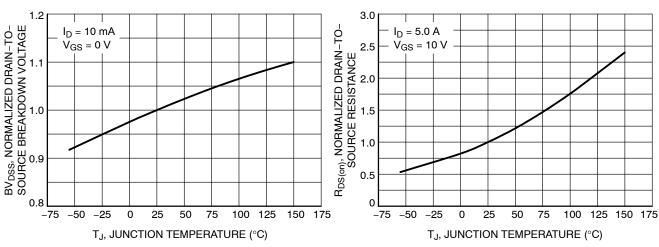


Figure 7. Breakdown Voltage Variation vs. Temperature

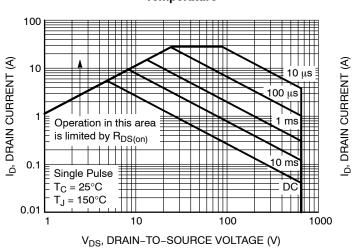


Figure 9. Maximum Safe Operating Area

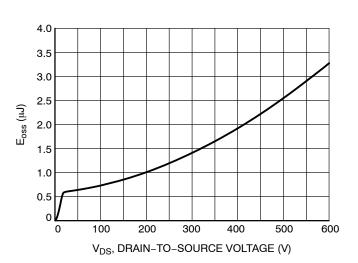
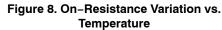


Figure 11. E_{oss} vs. Drain-to-Source Voltage



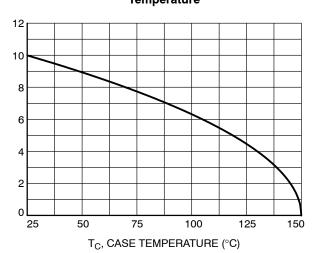


Figure 10. Maximum Drain Current vs. Case Temperature

TYPICAL CHARACTERISTICS

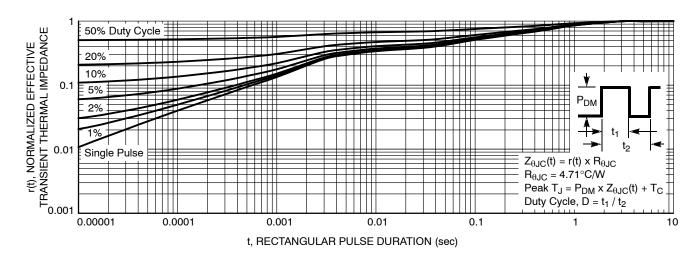


Figure 12. Transient Thermal Response Curve

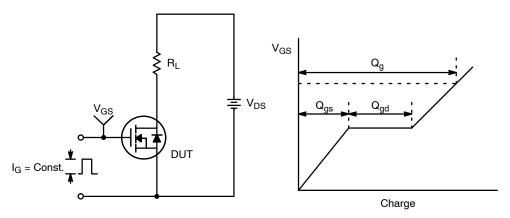


Figure 13. Gate Charge Test Circuit & Waveform

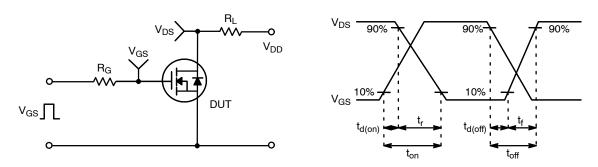


Figure 14. Resistive Switching Test Circuit & Waveforms

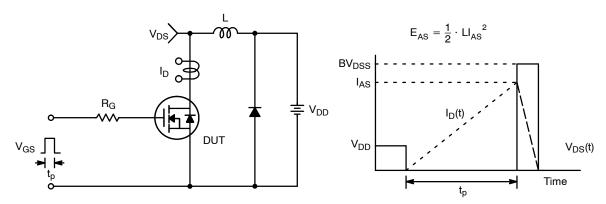


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

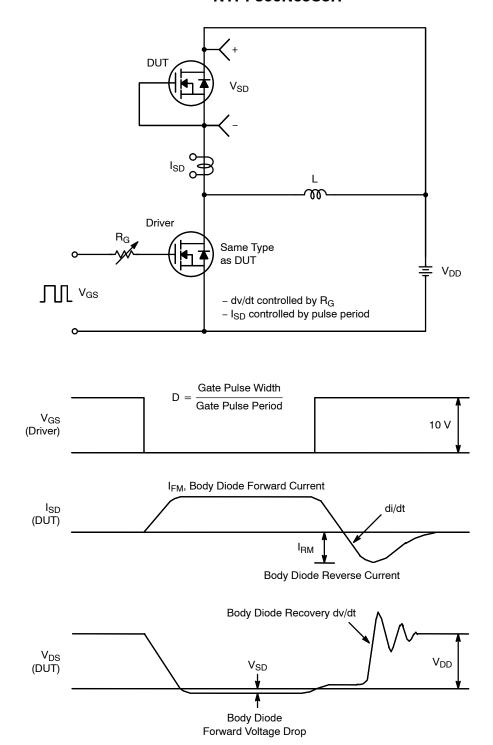


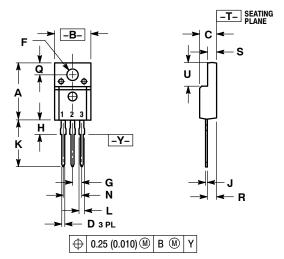
Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

SUPERFET is a registered trademark of Semiconductor Components Industries, LLC (SCILLC) or its subsidiaries in the United States and/or other countries.

PACKAGE DIMENSIONS

TO-220 FULLPAK

CASE 221D-03 ISSUE K



NOTES

- DIMENSIONING AND TOLERANCING PER ANSI
 Y14 5M 1982
- 2. CONTROLLING DIMENSION: INCH
- 221D-01 THRU 221D-02 OBSOLETE, NEW STANDARD 221D-03.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
Α	0.617	0.635	15.67	16.12
В	0.392	0.419	9.96	10.63
С	0.177	0.193	4.50	4.90
D	0.024	0.039	0.60	1.00
F	0.116	0.129	2.95	3.28
G	0.100 BSC		2.54	BSC
Н	0.118	0.135	3.00	3.43
J	0.018	0.025	0.45	0.63
K	0.503	0.541	12.78	13.73
L	0.048	0.058	1.23	1.47
N	0.200 BSC		5.08 BSC	
Q	0.122	0.138	3.10	3.50
R	0.099	0.117	2.51	2.96
S	0.092	0.113	2.34	2.87
U	0.239	0.271	6.06	6.88

ON Semiconductor and the are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor and see no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:
Email Requests to: orderlit@onsemi.com

ON Semiconductor Website: www.onsemi.com

TECHNICAL SUPPORT
North American Technical Support:
Voice Mail: 1 800–282–9855 Toll Free USA/Canada

Voice Mail: 1 800–282–9855 Toll Free USA/Canac Phone: 011 421 33 790 2910 Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative